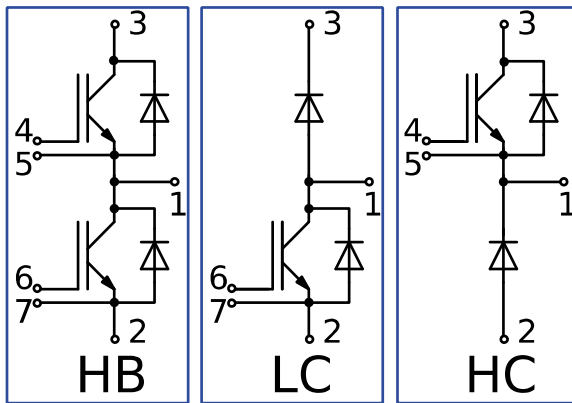
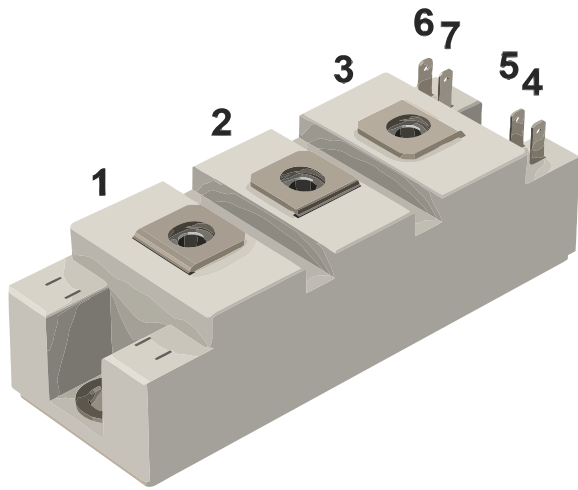


**Industry standard 34mm IGBT module**
**1200V 100A**

**Chip features**

- IGBT Chip
  - low  $V_{CE(sat)}$  value
  - 10  $\mu s$  short circuit @ 150°C
  - square RBSOA @  $2xI_C$
  - low gate charge
  - low EMI
- FRD Chip
  - fast and soft reverse recovery
  - low voltage drop

**Design features**

- copper baseplate
- $Al_2O_3$  DBC substrate
- ultrasonically welded power terminals
- improved thermal cycling
- RoHS compliant

**Typical application**

- AC motor drives
- solar inverter
- air conditioning
- high power converters and UPS

**Maximum rated values**

Definition	Symbol	Conditions	Value	Unit
<b>IGBT</b>				
Collector-Emitter voltage	$V_{CES}$	$V_{GE} = 0V$	1200	V
Collector current (nominal)	$I_{C\ nom}$		100	A
Collector current (maximum continuous)	$I_{C\ 25}$	$T_j = 175^\circ C, T_c = 25^\circ C$	159	A
	$I_{C\ 80}$	$T_j = 175^\circ C, T_c = 80^\circ C$	121	A
Repetitive peak collector current *1	$I_{CRM}$	$I_{CRM} = 3 \times I_{C\ nom}, t_p = 1ms$	300	A
Gate-Emitter voltage	$V_{GES}$		$\pm 20$	V
Junction temperature	$T_j$		-40 ... 175	°C
<b>Inverse diode / Freewheeling diode</b>				
Repetitive peak reverse voltage	$V_{RRM}$	$V_{GE} = 0V$	1200	V
Forward current (nominal)	$I_{F\ nom}$		100	A
Forward current (maximum continuous)	$I_{F\ 25}$	$T_j = 175^\circ C, T_c = 25^\circ C$	129	A
	$I_{F\ 80}$	$T_j = 175^\circ C, T_c = 80^\circ C$	94	A
Repetitive peak forward current *1	$I_{FRM}$	$I_{FRM} = 3 \times I_{F\ nom}, t_p = 1ms$	300	A
Surge (non-repetitive) forward current	$I_{FSM}$	$t_p = 1ms, \sin 180^\circ, T_j = 25^\circ C$	550	A
Junction temperature	$T_j$		-40 ... 175	°C
<b>Module</b>				
Storage temperature	$T_{stg}$		-40 ... 125	°C
Isolation voltage	$V_{isol}$	AC sinus 50 Hz, $t = 1min$	4000	V

\*1 Pulse width and repetition rate should be such that device junction temperature ( $T_j$ ) does not exceed maximum  $T_j$  rating.



**Characteristics**

Definition	Symbol	Conditions	Value			Unit	
			min.	typ.	max.		
<b>IGBT</b>							
Collector-Emitter saturation voltage	$V_{CEsat}$ (chip)	$V_{GE} = 15V$ $I_C = 100A$	$T_J = 25^\circ C$	-	1.75	2.2	V
			$T_J = 150^\circ C$	-	2.2	2.5	V
	$V_{CEsat}$ (terminal)		$T_J = 25^\circ C$	-	1.85	2.3	V
			$T_J = 150^\circ C$	-	2.3	-	V
Gate-Emitter threshold voltage	$V_{GE(th)}$	$I_C = 4mA, V_{CE} = V_{GE}, T_J = 25^\circ C$	5.5	6	6.5	V	
Collector-Emitter cut-off current	$I_{CES}$	$V_{CE} = 1200V$ $V_{GE} = 0V$	$T_J = 25^\circ C$	-	100	300	$\mu A$
			$T_J = 150^\circ C$	-	900	2000	$\mu A$
Gate-Emitter leakage current	$I_{GES}$	$V_{CE} = 0V, V_{GE} = \pm 20V$	-	-	500	nA	
Input capacitance	$C_{ies}$	$V_{CE} = 25V, V_{GE} = 0V$ $f = 1MHz, T_J = 25^\circ C$	-	6010	-	pF	
Output capacitance	$C_{oes}$		-	590	-	pF	
Reverse transfer capacitance	$C_{res}$		-	589	-	pF	
Total gate charge	$Q_G$		$I_C = 100A, V_{CE} = 600V, V_{GE} = -8 \div 15V$	-	1150	-	nC
Internal gate resistance	$R_{Gint}$	$T_J = 25^\circ C$	-	5	-	$\Omega$	
Turn-on delay time	$t_{d(on)}$	$V_{CE} = 600V, I_C = 100A,$ $R_G = 1.5\Omega, V_{GE} = \pm 15V,$ $T_J = 150^\circ C,$ $di/dt_{on} = 3230 A/\mu S,$ $di/dt_{off} = 1330 A/\mu S,$ $du/dt_{off} = 9350 V/\mu S$	-	294	352.8	ns	
Rise time	$t_r$		-	38	45.6	ns	
Turn-on energy	$E_{on}$		-	10.7	12.8	mJ	
Turn-off delay time	$t_{d(off)}$		-	418	501.6	ns	
Fall time	$t_f$		-	62	74.4	ns	
Turn-off energy	$E_{off}$		-	8.7	10.4	mJ	
Short circuit duration	$t_{psc}$		$V_{CE} = 900V, V_{GE} = 15V,$ $T_J = 150^\circ C, \text{non-repetitive}$	-	-	10	$\mu s$
Collector-emitter threshold voltage	$V_{CE0}$		$V_{GE} = 15V, T_J = 150^\circ C$	-	0.88	0.98	V
On-State slope resistance (IGBT)	$r_{CE0}$	for static power loss calculation	-	13.2	15.2	m $\Omega$	
Thermal resistance junction to case	$R_{th(j-c)}$	per IGBT	-	-	0.27	K/W	
<b>Inverse diode / Freewheeling diode</b>							
Continuous forward voltage	$V_F$ (chip)	$I_F = 100A$	$T_J = 25^\circ C$	-	1.9	2.2	V
			$T_J = 150^\circ C$	-	1.9	-	V
	$V_F$ (terminal)		$T_J = 25^\circ C$	-	2.0	2.3	V
			$T_J = 150^\circ C$	-	2.0	-	V
Reverse recovery time	$t_{rr}$	$V_R = 600V$ $I_F = 100A$ $di_F/dt = 2500 A/\mu S$	$T_J = 25^\circ C$	-	200	-	ns
			$T_J = 125^\circ C$	-	350	-	ns
Peak reverse recovery current	$I_{RM}$		$T_J = 25^\circ C$	-	75	-	A
			$T_J = 125^\circ C$	-	100	-	A
Reverse recovered charge	$Q_{rr}$		$T_J = 25^\circ C$	-	6	-	$\mu C$
			$T_J = 125^\circ C$	-	12.5	-	$\mu C$
Reverse recovery energy	$E_{rr}$		$T_J = 25^\circ C$	-	1.8	-	mJ
			$T_J = 125^\circ C$	-	4	-	mJ
Forward threshold voltage (Diode)	$V_{F0}$	$T_J = 175^\circ C$	-	1.2	-	V	
On-state slope resistance (Diode)	$r_F$	for static power loss calculation	-	9	-	m $\Omega$	
Thermal resistance junction to case	$R_{th(j-c)}$		-	-	0.49	K/W	
<b>Module</b>							
Parasitic inductance Collector-Emitter	$L_{CE}$		-	30	-	nH	
Resistance terminal-chip	$R_{CC'+REE'}$	terminal-chip $T_J = 25^\circ C$	-	0.65	-	m $\Omega$	
Thermal resistance case to heatsink	$R_{thCH}$	per module	-	0.05	-	K/W	
Mounting torque for screws to heatsink	$M_s$	to heatsink M6	3	-	5	Nm	
Mounting torque for terminal screws	$M_t$	to terminals M5	2.5	-	5	Nm	
Weight	$W$		-	-	170	g	

